Broadband Deep UV to NIR Photodetection with High Stability and Large Dichroic Ratio Enabled by Type-I Band Engineering

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Abstract

Van der Waals (vdWs) heterostructures formed from two-dimensional (2D) layered materials have opened promising avenues in broadband photodetection, particularly in polarization-sensitive applications. Previous research indicates that type-I heterostructures hold considerable potential for broadband polarization photodetector development; however, achieving high polarization sensitivity in these vdWs heterostructures remains insufficiently explored. In this work, we systematically present combined theoretical and experimental studies on designing and fabricating a high-performance photodetector based on the InSe/TiS3 vdWs heterostructure exhibiting type-I band alignment. Theoretical studies supported by experimental verifications confirmed the presence of type-I band alignment between InSe and TiS₃. Leveraging this favourable band alignment, the fabricated device demonstrated broadband photodetection spanning the deep ultraviolet to nearinfrared spectral range along with pronounced polarization sensitivity. The photodetector exhibited superior performance metrics, including a high responsivity of 55 A/W-1, detectivity of 1.80×10¹³ Jones, an external quantum efficiency reaching 15633%, and a rapid response time of approximately 23.6 µs. Additionally, significant polarization sensitivity was observed, characterized by a notable dichroic ratio of approximately 5, emphasizing the device's potential for advanced optoelectronic applications. This study provides valuable insights and a practical reference for the development of high-performance polarized photodetectors across a broad spectral range.

Keywords: Two-dimensional (2D) materials; van der Waals (vdWs) heterostructures; type-I band alignment; broadband photodetection; polarization sensitivity

References

- [1] Schaibley, J. R.; Yu, H.; Clark, G.; Rivera, P.; Ross, J. S.; Seyler, K. L.; Yao, W.; Xu, X. Valleytronics in 2D materials. Nature Reviews Materials 2016, 1, 1-15.
- [2] Ahmad, W.;Gong, Y.;Abbas, G.;Khan, K.;Khan, M.;Ali, G.;Shuja, A.;Tareen, A. K.;Khan, Q.; Li, D. Evolution of low-dimensional material-based field-effect transistors. Nanoscale 2021, 13, 5162-5186.
- [3] Novoselov, K. S.; Mishchenko, A.; Carvalho, A.; Castro Neto, A. 2D materials and van der Waals heterostructures. Science 2016, 353, aac9439.
- [4] Ahmad, W.;Pan, L.;Khan, K.;Jia, L.;Zhuang, Q.; Wang, Z. Progress and insight of Van der Waals heterostructures containing interlayer transition for near Infrared photodetectors. Advanced Functional Materials 2023, 33, 2300686.
- [5] Long, M.; Wang, P.; Fang, H.; Hu, W. Progress, challenges, and opportunities for 2D material based photodetectors. Advanced Functional Materials 2019, 29, 1803807.

Figures

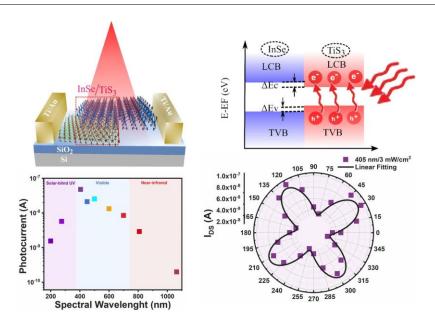


Figure 1: Table of contents figure for vdWs heterostructure for type-I band alignment based on InSe/TiS₃ showing broadband spectrum response spanning from deep UV to NIR detection and competitive polarization detection.